T 000	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
LTR A	Add vendor CAGE U4637 and 69210. Add case outlines T and U. Change test limits for line regulation, load regulation, standby current drain, and standby current drain with line tests. Change test conditions for line regulation and output voltage tests. Add temperature characterization for ripple rejection test. Change footnotes 1/, 2/, and 5/ in table I.	89-07-24	M. A. Frye
В	Add case outline 2. Change to test conditions in table I. Editorial changes throughout.	92-09-15	M. A. Frye
С	Add device type 02. Add case outline P. Technical and editorial changes throughout.	93-11-09	M. A. Frye
D	Add device type 03. Technical and editorial changes throughout.	94-04-04	M. A. Frye

THE ORIGINAL FIRST PAGE OF THIS DRAWING HAS BEEN REPLACED.

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REV																				
SHEET																				
REV	D																			
SHEET	15																ļ			
REV STATUS			RE	V		D	D	D	D	D	D	D	D	D	D	D	D	D	D	
OF SHEETS	3			SH	EET		1	2	3	4	5	6	7	8	9	10	11	12	13	14
PMIC N/A PREPARED BY Charles E Besore DEFENSE ELECTRONICS SU DAYTON, OHIO						PPLY 454	CEN' 44	TER												
MII	STANDARDIZED MILITARY DRAWING				CHECKED BY Ray Monnin															
THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE			APPROVED BY D A DiCenzo					MICROCIRCUIT, LINEAR, POSITIVE 5- VOLT REGULATOR, MONOLITHIC SILICON							1					
				DRAW	ING A	PPROVAI	L DATE													
AMSC N/A			88-0	7-28				SIZ	E		E CO			5	962-	-877	82			
				REVI	SION	LEVEL				A		1	6726	8	<u> </u>					
							D			SH	EET		1		OF	15				

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<u>DISTRIBUTION STATEMENT A</u>. Approved for public release; distribution is unlimited.

5962-E153-94

9004708 0001111 165 📟

1. SCOPE

1.1 <u>Scope</u>. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:

<u>5962-87782</u>	_01_	<u>P</u>	X
Drawing number	Device type	Case outline	Lead finish
	(see 1.2.1)	(see 1.2.2)	(see 1.2.3)

1.2.1 Device type(s). The device type(s) shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	7805A (see terminal connections, case 2)	Positive regulator, 5-volt fixed
02 03 <u>1</u> /	78MO5M 78O5A (see terminal connections, case 2)	Positive regulator, 5-volt fixed Positive regulator, 5-volt fixed

1.2.2 <u>Case outline(s)</u>. The case outline(s) shall be as designated in MIL-STD-1835, and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
N	See figure 1	3	Surface mount
P	GDIP1-T8 or CDIP2-T8	8	Dual-in-line
T	See figure 1	3	TO-257 flange mounted
U	See figure 1	3	TO-257 flange mounted with isolated tab
X	See figure 1	3	TO-39 can
Y	See figure 1	2	TO-3 can
Z	MBFM4-P2	2	T0-66 can
2	CQCC1-N2D	20	Square leadless chip carrier

1.2.3 <u>Lead finish</u>. The <u>lead finish</u> shall be as specified in MIL-STD-883 (see 3.1 herein). Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

1.3 Absolute maximum ratings.

Input voltage:	
Operating or output shorted to ground (device types 01, 02 and 03)	35 V dc
Transient (device type 01 and 03)	43 V dc 2/
Output current (I _O)	
Cases P, X and Ž (device type O1 and O3)	0.5 A
Cases Y, Z, T, N, and U (device type O1 and O3)	1.0 A
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+300°C
Case temperature, case outline 2 (soldering, 10 seconds):	
Device type 02	+260°C
Power dissipation (P _D):	
T _C = +25°C:	
Device type O1 and O3, cases X and 2	2 W
Device type O1, case Y	20 W
Device type D1, cases Z, T, and U	15 W

1/ Device type 03 has been added only to incorporate a different pinout for case outline 2.
2/ The 43-volt input rating refers to the ability of the regulator to withstand high line or transient conditions without damage. Since the regulator's maximum current capability is reduced, the output may fall out of regulation at high input voltages under nominal loading.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	SIZE A		5962-87782
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 Absolute maximum ratings - Continued. Power dissipation (Pn) - continued: T_A = +25°C:
Device type 01 and 03, cases X and 2 1375 mW 4/ Thermal resistance, junction-to-case (Θ_{JC}) : See MIL-STD-1835 3.5°€/W 4.2°C/W 15°C/W 3°C/W 6°C/W Case 2 See MIL-STD-1835 Thermal resistance, junction-to-ambient (Θ_{JA}): Cases N, X, and 2 (device type 01 and 03) Case Y (device type 01) 42°C/W 110°c/w Case 2 (device type 02) 65°C/W +150°C <u>5</u>/ Junction temperature (T,) 1.4 Recommended operating conditions. Ambient operating temperature range (T_A) Input voltage range (V_{IN}) +8 V dc to +25 V dc 2. APPLICABLE DOCUMENTS 2.1 Government specification, standards, and bulletin. Unless otherwise specified, the following specification, standards, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein. SPECIFICATION MIL ITARY MIL-I-38535 Integrated Circuits (Microcircuits) Manufacturing, General Specification for. STANDARDS MILITARY - Test Methods and Procedures for Microelectronics. MIL-STD-883 - Microcircuit Case Outlines. MIL-STD-1835 BULLETIN MILITARY MIL-BUL-103 - List of Standardized Military Drawings (SMD's). (Copies of the specification, standards, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.) $\frac{3}{}$ Derate at 8.4 mW/°C above T_A = +25°C. $\frac{4}{}$ Derate at 11.0 mW/°C above T_A = +25°C. $\frac{5}{}$ The device is protected by a thermal shutdown circuit which is designed to turn off the output transistor whenever the device junction temperature is in excess of +150°C. STANDARDIZED SIZE 5962-87782 MILITARY DRAWING A DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 REVISION LEVEL SHEET 3 D

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2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-I-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-I-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-I-38535 is required to identify when the QML flow option is used.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-STD-883 (see 3.1 herein) and herein.
 - 3.2.1 <u>Case outline(s)</u>. The case outlines shall be in accordance with 1.2.2 herein and on figure 1.
 - 3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table 1 and shall apply over the full ambient operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 <u>Marking</u>. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).
- 3.6 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-EC prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.8 <u>Notification of change</u>. Notification of change to DESC-EC shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.9 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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Test Symbol		Conditions 1/	Device	Group A	Limits		Unit
	<u> </u>	-55°C ≤ T _A ≤ +125°C unless otherwise specified	types	subgroups	Min	Max	<u> </u>
Output voltage	V _{ОUТ}	T _A = +25°C	01, 03	1	4.92	5.08	V
] 	T _A = +25°C	02	1	4.8	5.2	
	 	V _{IN} = 7.5 V to 20 V <u>2</u> /	01, 03	1, 2, 3	4.85	5.15	
		 V _{IN} = 8.0 V to 20 V <u>2</u> /	02	 1, 2, 3 	4.7	5.3)
dipple rejection <u>3</u> /	∆v _{in}	 f = 120 Hz,	01, 03	4	68		dB
AVOUT	V _{IN} = 8 V to 18 V		5, 6 <u>4</u> /	60		! 	
		 f = 120 Hz, I _{QUT} = 100 mA, V _{IN} = 8 V to 18 V 	02	 4,5,6 <u>4</u> / 	62		;
		f = 120 Hz, I _{OUT} = 300 mA, V _{IN} = 8 V to 18 V	- 	4 4/	62		
ine regulation	VRLINE	-55°C \le T _J	01, 03	11		5	mV
		≤ +125°C	-	2, 3	<u> </u>	12	
		$3/5/V_{IN} = 8.0 V to 12 V$	i	11		4	
				2, 3	,	10	
	i	T = 125 °C V = 7.0 V + 25 V	02	1	. I	50	
	!	T _A = +25 °C V _{IN} = 7.0 V to 25 V	_ 02		 	JU	

 $I_0 = 500 \text{ mA} \frac{7}{}$

 $I_0 = 350 \text{ mA}$

T_A ≈ <25°C

See footnotes at end of table.

V_{DO}

Dropout voltage

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01, 03

02

1

2.5

2.5

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Test	Symbol		Conditions 1/				Group A	Lim	its	Uni
	1	-55°C unless ot	<pre></pre>	types	subgroups	Min	Max			
oad regulation	VRLOAD	 -55°C	I _O = 5.0 mA <u>6</u> / to 1.5 A	01, 03	1	<u> </u> 	12	m∨		
		<u>3</u> /	I _O = 5.0 mA <u>6/</u> to 1.0 A	01, 03	2, 3	<u> </u> 	25			
			I _O = 250 mA <u>6</u> / to 750 mA	01, 03	1		6 15			
		 	I _O = 5 mA <u>7</u> / to 500 mA	01, 03	2, 3		25			
		[to 500 mA	1	2, 3	<u> </u> 	50	 		
		T _A = +25 °C	I _O = 5 mA to 500 mA	02	1		50	<u> </u>		
	 	 	$I_0 = 5 \text{ mA to } 200 \text{ mA}$				25			
tandby current drain	ISCD] 		01, 03	1		6.0	mA		
		 			2, 3	<u> </u>	6.5			
tandby current drain change with line	 AI _{SCD}	 V _{IN} = 7.5 V t	o 20 V	01, 03	1, 2, 3	 	7.0	 mA		
change with time	1	V _{IN} = 8.0 V t	o 25 V, I _O = 200 mA	02	1, 2, 3	 	0.8	 		
tandby current drain change with load	AI _{SCD}	I _O = 5.0 mA t	o 1 A <u>6</u> /	01, 03	1, 2, 3		0.5	 mA		
•		I _O = 5.0 mA t	o 500 mA <u>7</u> /			 		 		
		 I _O = 5.0 mA t	o 350 mA	 02 	1, 2, 3		0.5	 		
Peak output current	I _{O(pk)}	 T _A = +25°C	<u>6</u> /	01, 03	 1 	1.5	3.3	 A		
			7/	; } !	 	0.5	1.7			
			4/	02	1 1	0.5	1.4			

See footnotes at end of table.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/	Device	Group A	Lim	its	Unit
		unless otherwise specified	-55°C ≤ T _A ≤ +125°C types ess otherwise specified		Min	Max	<u> </u>
Short circuit current 8/	Ios	v _{IN} = 35 v	01, 03	11		1.2	A
<u>-</u> -		<u> </u>		2, 3		2.8	
		7/		1		0.7	
				2, 3		2.0	
	1		02	1		0.6	
Output noise voltage <u>4</u> /	N _O	 T _A = +25°c, f = 10 Hz to 100 kHz	01, 03	7		40	μV/V rms
			02	7	<u> </u>	200	μν
Long term stability 4/	I ∆V _{OUT} / ∆t	T _A = +25°C, t = 1,000 hrs	01, 03	7		75	 mV
Temperature coefficient 4/	∆T/∆t	T _A = -55°C to +25°C, I _O = 5.0 mA	 02 	1, 3		 -2 	 mV/°
		 T _A = +25°C to +125°C, I _O = 5.0 mA	 	1, 2	 	-1.5	

 $[\]underline{1}$ / Unless otherwise specified, for device type 01 and 03, V_{IN} = 10 V and I_{O} = 500 mA for cases Y, Z, T, N, and U, V_{IN} = 10 V and I_{O} = 100 mA for cases X and 2. Maximum test current for cases X and 2 is 500 mA. For device type 02, V_{IN} = 10 V and I_{O} = 350 mA for cases P and 2.

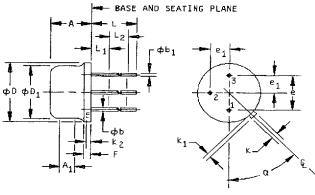
- 4/ Guaranteed, if not tested, to the limits specified.
- 5/ Minimum load current for full line regulation is 5.0 mA.
- 6/ For cases Y, Z, T, N, and U only.
- $\underline{7}$ / For cases X and 2 only.
- $\underline{8}/$ Short circuit protection is only assured up to V_{IN} = 35 V.

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 $[\]underline{2}$ / For device type 01 and 03, cases P, X and 2: $\underline{I_0}$ = 5 mA to 500 mA, P \leq 2 W. For device type 01, case Y: $\underline{I_0}$ = 5 mA to 1.0 A, P \leq 20 W. For device type 01, cases Z, T, N, and U: $\underline{I_0}$ = 5 mA to 1.0 A, P \leq 15 W. For device type 02, cases P and 2: $\underline{I_0}$ = 5 mA to 350 mA, P \leq 1.3 W.

^{3/} All measurements except output noise voltage and ripple rejection are made at constant junction temperature and with low duty cycle.

Case outline X



	Inc	hes	 Millim	eters	
Ltr	Min	Max	Min	Max	Notes
A	.165	185	4.19	4.70	<u> </u>
φ b	.016	.019	0.41	0.48	2
<i>φ</i> ₆ 1	.016	.021	0.41	0.53	2
Φ0	.335	370	8.51	9.40	
φ _D ₁	.305	. 335	7.75	8.51	
e	.20	O_T.P.	5.0	08 T.P.	4
e ₁	.100) T.P.	2.	54 T.P.	4
F		.050		1.27	
k	.028	. 034	0.71	0.86	
k ₁	.029	.045	0.74	1.14	3
k ₂	.009	.041	0.23	1.04	
L	.500		12,70		
Lq		.050	. 	1.27	
L ₂	 ₋ 250		6.35		
α	45° T.	P	45°	' T.P.	

NOTES:

- The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.
- 2. (All leads) ϕ b applies between L₁ and L₂. ϕ b₁ applies between the L₂ and .500 (12.70 mm) from the reference plane. Diameter is uncontrolled in L₁ and beyond .500 (12.70 mm) from the reference plane.
- Measured from the maximum diameter of the product.
- 4. Leads having a maximum diameter of .019 (0.48 mm) measured in gauging plane .054 (1.37 mm) + .001 (0.03 mm) -.000 (0.00 mm) below the base plane of the product shall be within .007 (0.18 mm) of their true-position relative to a maximum width tab.
- The product may be measured by direct methods or by gauge.

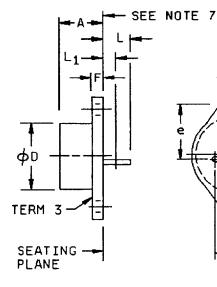
FIGURE 1. <u>Case outlines</u>.

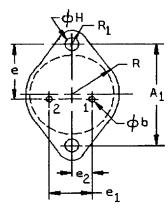
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Case outline Y





	Inc	hes	Millim	eters	
Ltr	Min	Max	Min	Max	Notes
A	.250	450	6.35	11.43	
A ₁	1.177	 1.197 	29.90	30.40	
φю	.038	.043	.97	1.09	2, 6
фΣ		.875	<u> </u>	 22.22	
e	.655	.675	16.64	 17.14	<u> </u>
e ₁	.420	.440	10.67	11.16	
e ₂	.205	_225	5.21	5.72	
F	.060	. 135	1.52	3.43	
фн	.151	.161	3.84	4.09	4, 5
<u></u>	.312	.500	7.92	12.70	3
L ₁		.050		1.27	2, 3
R	.495	.525	 12.57	13.34	
R ₁	.131	.188	3.33	4.78	

NOTES:

- The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.
- 2. (Two leads) ϕ b applies between L₁ and .500 (12.70 mm) from the seating plane. Diameter is uncontrolled in L₁ and beyond .500 (12.70 mm) from the seating plane.
- 3. Two leads.
- 4. Two holes.
- Two holes located at true position within diameter .010 (0.25 mm).
- Leads having a maximum diameter of .043 (1.09 mm) measured in gauging plane .054 (1.37 mm) +.001 (0.03 mm) -.000 (0.00 mm) below the seating plane shall be located at true position within diameter .014 (0.36 mm).
- The mounting surface of the header shall be flat to convex within .003 (0.08 mm) inside a .930 (23.62 mm) diameter circle on the center of the header and flat to convex within .006 (0.15 mm) overall.

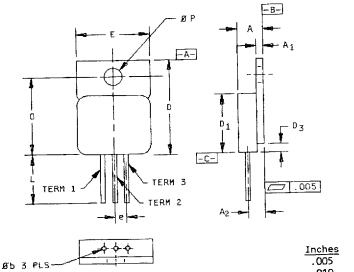
FIGURE 1. <u>Case outlines</u> - Continued.

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Case outlines T and U



⊕.020⊕©A⊕B ⊕.010⊕©

Tuches	189535
.005	0.13
.010	0.25
.020	0.51

Millimeters Inches Min Max Min 200 4.83 5.08 190 1.14 .045 0.89 .035 3.05 BSC BSC .120 A2 035 0.64 .89 .025 .645 665 16.38 16.89 10.92 10.41 .410 .430 1.65 .000 .065 0.00 D3 BSC 2.54 BSC 100 10.41 10.71 410 422 500 750 12.70 537 13.39 16.64 527 140 150 3.56

NOTE:

The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inchpound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

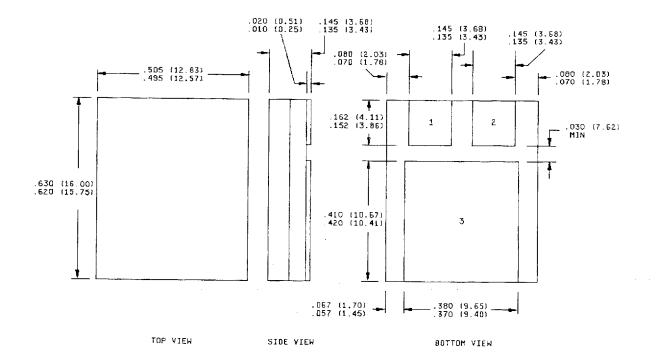
FIGURE 1. <u>Case outlines</u> - Continued.

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PINOUT
1 IN
2 OUT
3 GROUND

NOTE:

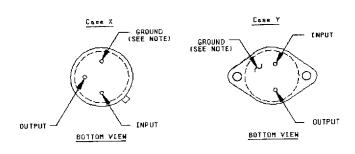
The US government preferred system of measurement is the metric SI system. However, since this item was originally designed using inch-pound units of measurement, in the event of conflict between the metric and inch-pound units, the inch-pound units shall take precedence.

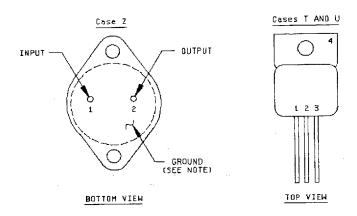
FIGURE 1. <u>Case outlines</u> - Continued.

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NOTE: Case is connected to ground.

Case T

1 - Input
2 - Ground
3 - Output
4 - Ground
4 - No connection

FIGURE 2. Terminal connections.

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Device types	01)2	03
Case outlines	2	2	Р	2
Terminal number		Termina	lsymbol	
4	NC	NC	GND	NC
1	1	GND	NC	GND
2	V _{IN} NC	NC	NC	NC
3	•	NC		NC
4	NC NC	NC NC	V _{IN} NC	NC
5	NC	NC NC		NC
6	NC NC	NC NC	V _{OUT}	NC
7	GND		NC NC	
8	NC I	NC NC	110	NC VIN
9	NC.			NC
10	v _{out}	NC NC		NC NC
11				NC NC
12	V _{OUT}	NC	ļ	NC
13		NC		NC NC
14	NC .	NC		l .
15	VOUT SENSE	V _{OUT}	·	VOUT
16	į NL j			NC NC
. 17	V _{IN} NC	NC)
18		NC		NC NC
19	NC	NC NC		NC NC

NOTE: For normal operation, $V_{\mbox{OUT}}$ SENSE must be connected externally to the load.

FIGURE 2. <u>Terminal connections</u> - Continued.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with method 5005, table I)	
 Interim electrical parameters (method 5004)	1	
 Final electrical test parameters (method 5004)	1*, 2, 3, 4**	
Group A test requirements (method 5005)	1, 2, 3, 4**, 5**, 6**, 7**	
 Groups C and D end-point electrical parameters (method 5005)	1	

- PDA applies to subgroup 1.
- ** Subgroups 4, 5, 6, and 7 if not tested shall be guaranteed to the limits specified in table I.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883:
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.
 - (2) $T_{\Delta} = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
 - 5. PACKAGING
- 5.1 <u>Packaging requirements</u>. The requirements for packaging shall be in accordance with MIL-STD-883 (see 3.1 herein).
 - 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

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- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444-5270, or telephone (513)
- 6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-EC.

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